

Electronic Supplementary Information for:

VUV-UV-vis photoluminescence, X-ray radioluminescence and energy transfer dynamics of Ce³⁺ and Eu²⁺ in Sr₂MgSi₂O₇

Donghao Wen ^a, Quanfeng Li ^a, Yiyi Ou ^a, Yunlin Yang ^a, Zeming Qi ^b, Pieter Dorenbos ^c, Hongbin Liang ^{*a}

^a *MOE Key Laboratory of Bioinorganic and Synthetic Chemistry, KLGHEI of Environment and Energy Chemistry, School of Chemistry, Sun Yat-sen University, Guangzhou 510006, China*

^b *National Synchrotron Radiation Laboratory, University of Science and Technology of China, Hefei 230029, China*

^c *Faculty of Applied Sciences, Delft University of Technology, 2629 JB, Delft, The Netherlands*

* E-mail: cesbin@sysu.edu.cn (Hongbin Liang).

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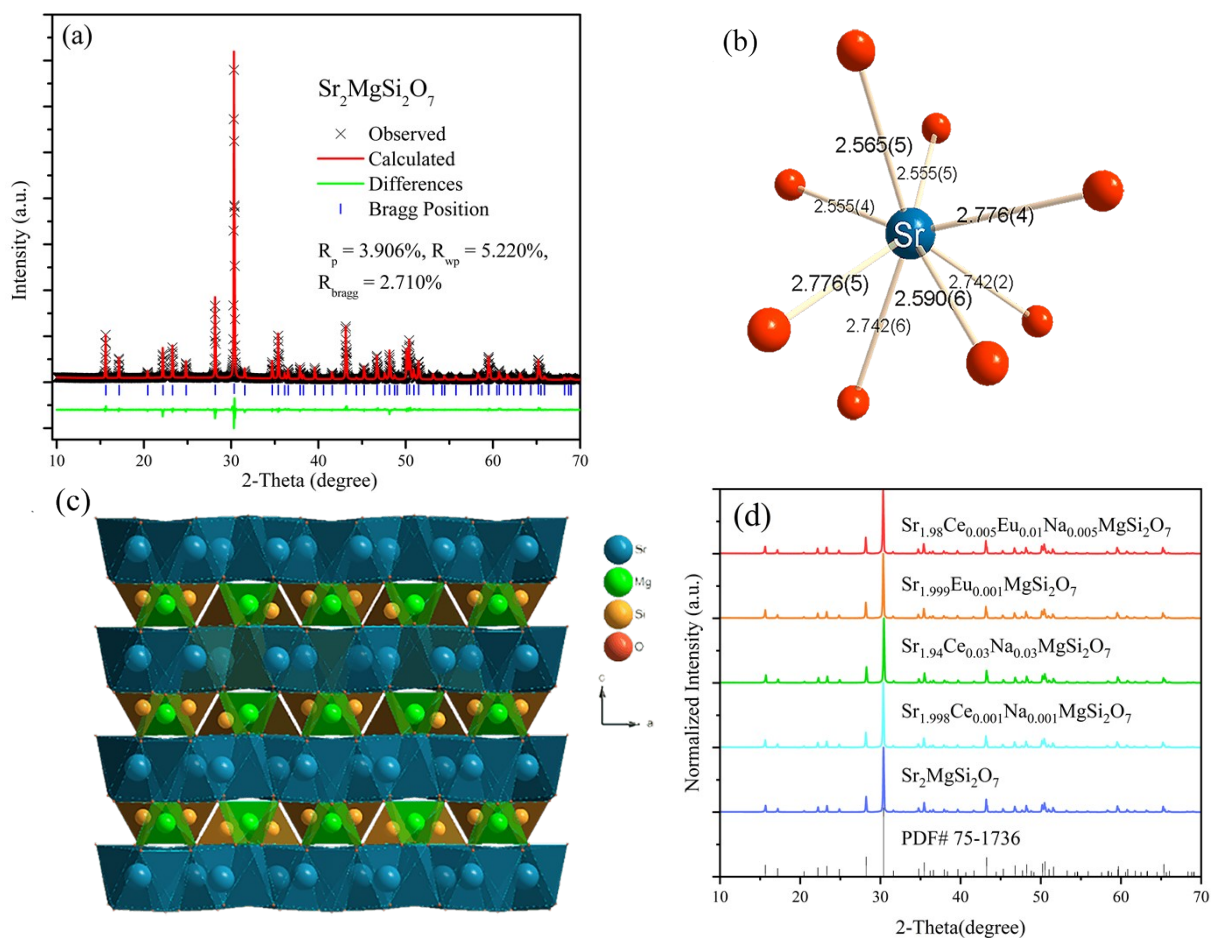


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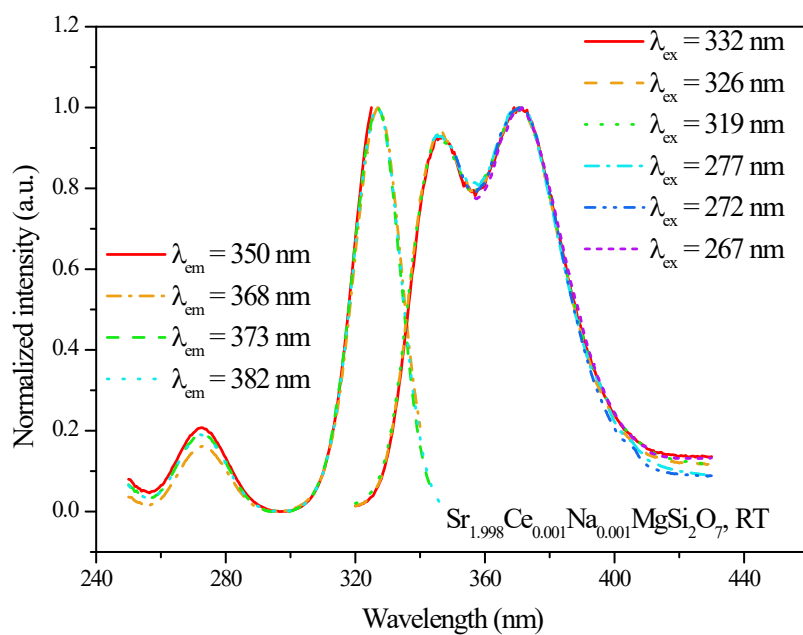


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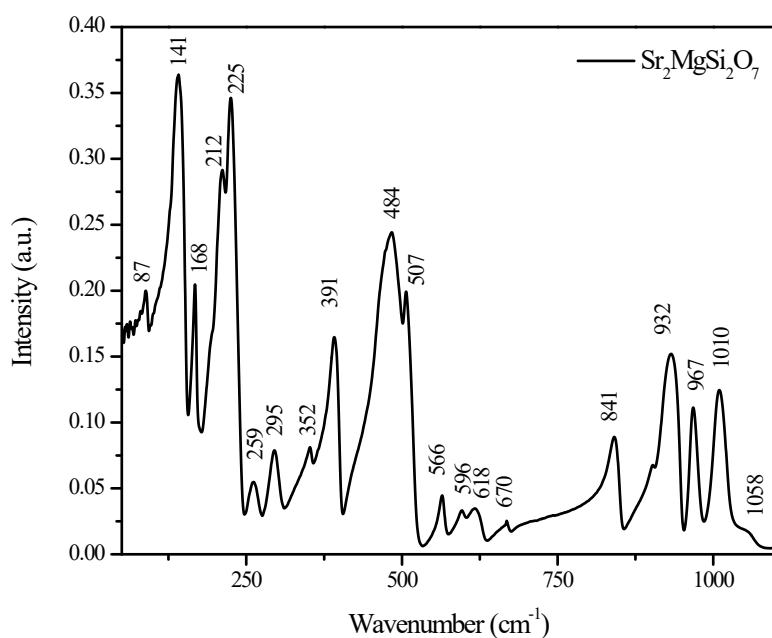


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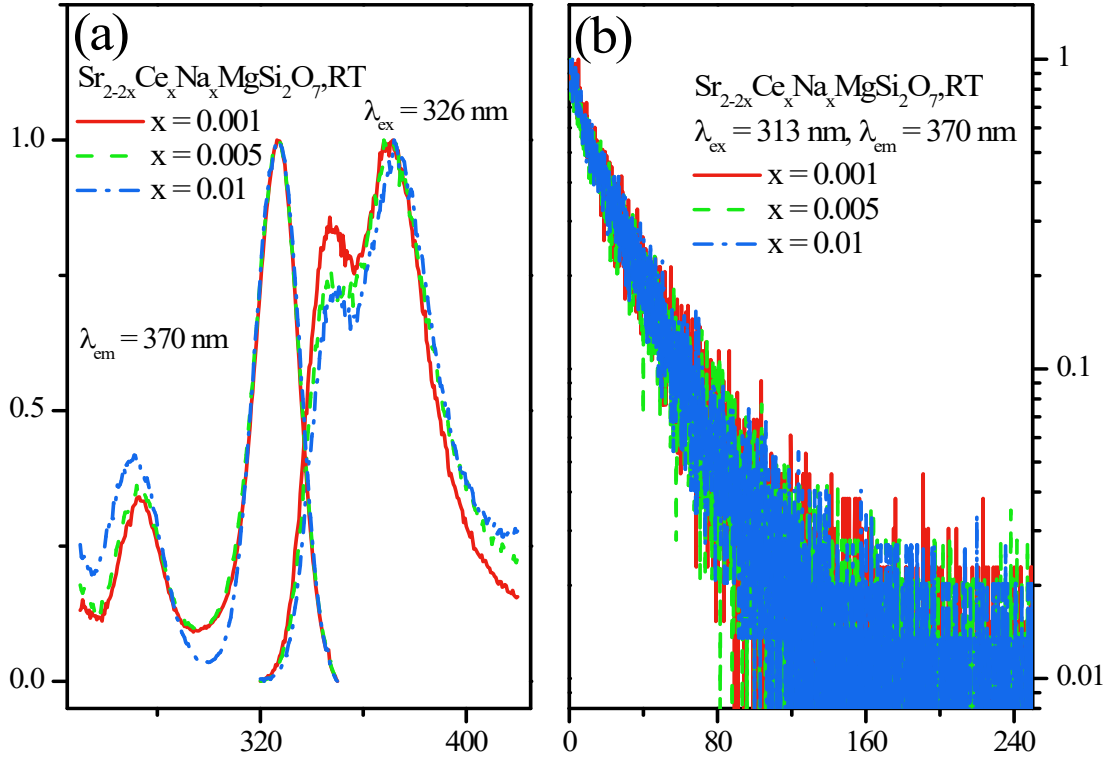


Fig. S4 (a) The height normalized excitation ($\lambda_{em} = 370$ nm) and emission ($\lambda_{ex} = 273$ nm) spectra and (b) luminescence decay curves ($\lambda_{ex} = 313$ nm, $\lambda_{em} = 370$ nm) of the samples $Sr_{2-2x}Ce_xNa_xMgSi_2O_7$ ($x = 0.001, 0.005, 0.03$) at RT.

The Ce^{3+} doping concentration dependent luminescence is studied. The height normalized excitation ($\lambda_{em} = 370$ nm) and emission ($\lambda_{ex} = 273$ nm) spectra of the samples $Sr_{2-2x}Ce_xNa_xMgSi_2O_7$ ($x = 0.001, 0.005, 0.03$) at RT are shown in Fig. S4(a) for comparison. The change of doping concentration of Ce^{3+} almost makes no difference to the excitation peak at ~ 326 nm, implying that the lowest 5d state energy is quite stable for different doping concentrations. The emission peak position of $5d-^2F_{5/2}$ remains unchanged at ~ 345 nm but the emission intensity ratio of $5d-^2F_{7/2}$ to $5d-^2F_{5/2}$ increases with the increasing concentrations due to the reabsorption.

The luminescence decay curves of the samples $Sr_{2-2x}Ce_xNa_xMgSi_2O_7$ ($x = 0.001, 0.005, 0.03$) at RT are shown in Fig. S4(b). All decay curves overlap with each other and follow exponential characteristic, and the lifetime is estimated to be

27.2 ns, implying that concentration quenching does not occur in the studied concentration range. The lifetime at RT in Fig. S4(b) is consistent with that at 78K in the inset of Fig. 1, implying that temperature quenching does not occur below RT.

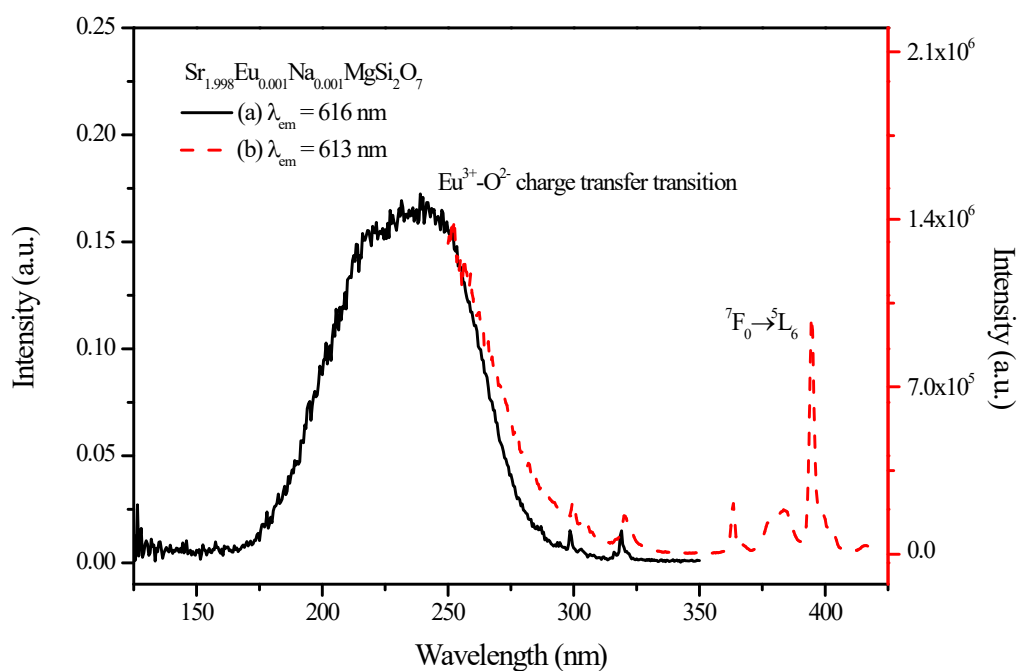


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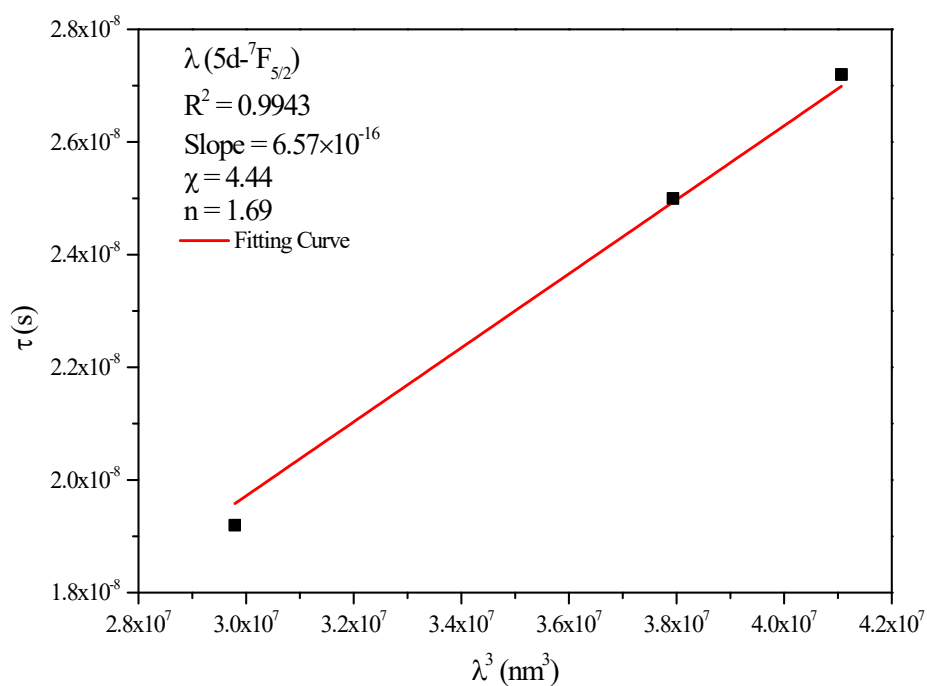


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Eu^{2+}	E_a (eV)	Γ_v (s^{-1})	Γ_0 (s^{-1})	R^2
Integrated intensity	0.226	1.73×10^6	1.84×10^{10}	0.989
Lifetime	0.252	1.76×10^6	4.83×10^{10}	0.999

Table S2 The S value, energy transfer microparameters (C_{DA}), energy migration microparameters (C_{DD}) and coefficients of determination of fitting procedure (R^2) via Inokuti-Hirayama (IH), Yokota-Tanimoto (YT) and Burshtein model.

Model	S	C_{DA} ($m^6 \cdot s^{-1}$)	C_{DD} ($m^6 \cdot s^{-1}$)	R^2
IH	6	2.89×10^{-45}	-	0.998
IH	8	1.82×10^{-62}	-	0.997
IH	10	7.98×10^{-80}	-	0.996
YT	6	2.35×10^{-46}	1.03×10^{-45}	0.992
Burshtein	6	1.16×10^{-46}	9.02×10^{-45}	0.997